

Notice of References Cited	Application/Control No. 10/631,952		Applicant(s)/Patent Under Reexamination KLASS, EDGARDO F.	
	Examiner Hai L. Nguyen		Art Unit 2816	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
X	A	US-6,711,724	03-2004	Yoshikawa, Atsushi	716/6
X	B	US-6,525,587	02-2003	Makino, Hiroshi	327/292
X	C	US-6,457,161	09-2002	Nadeau-Dostie et al.	716/6
X	D	US-6,331,800	12-2001	Radjassamy, Rajakrishnan	327/566
X	E	US-6,229,360	05-2001	Mizuno et al.	327/141
X	F	US-6,060,924	05-2000	Sugano, Hiroaki	327/202
X	G	US-5,969,551	10-1999	Fujioka, Shinya	327/149
X	H	US-5,903,175	05-1999	Miyashita, Takumi	327/218
X	I	US-5,864,252	01-1999	Tran et al.	327/202
X	J	US-5,742,190	04-1998	Banik et al.	327/152
X	K	US-5,487,092	01-1996	Finney et al.	375/354
X	L	US-5,162,667	11-1992	Yasui et al.	327/203
X	M	US-5,124,572	06-1992	Mason et al.	327/145

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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